

## 60V N-Channel Enhancement Mode MOSFET

### Description

The AP20N06DF uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 60V$   $I_D = 28A$

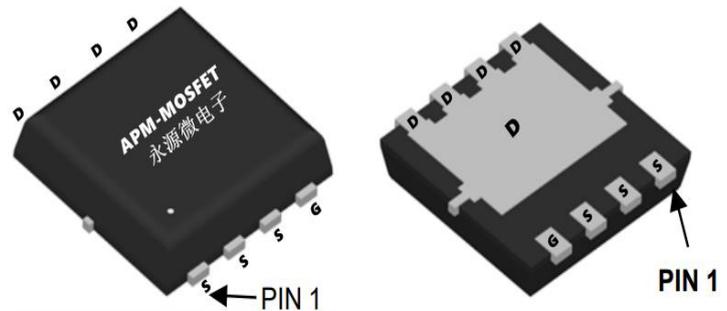
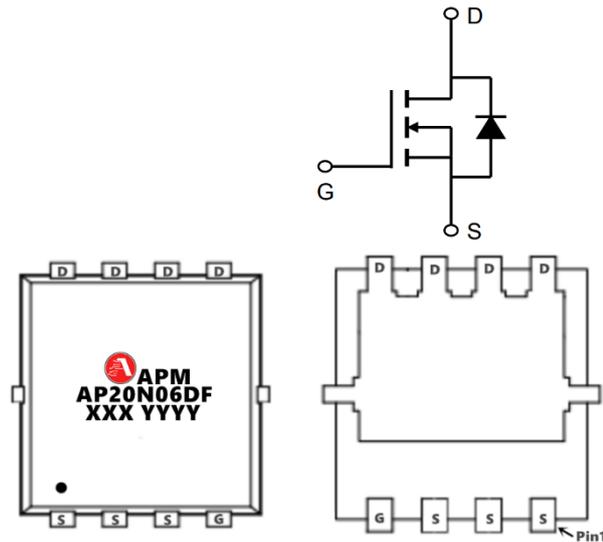
$R_{DS(ON)} < 35m\Omega$  @  $V_{GS}=10V$  (Type: **30mΩ**)

### Application

LED lamp

Load switch

Uninterruptible power supply



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP20N06DF	PDFN3X3-8L	AP20N06DF XXX YYYY	5000

### Absolute Maximum Ratings@ $T_J=25^\circ C$ (unless otherwise specified)

Symbol	Parameter	Max.	Units
$V_{DSS}$	Drain-Source Voltage	60	V
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	V
$I_D @ T_C=25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	28	A
$I_D @ T_C=100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	13	A
IDM	Pulsed Drain Current	74	A
IAS	Avalanche Current	13	A
EAS	Single Pulsed Avalanche Energy	22	mJ
$P_D @ T_C=25^\circ C$	Power Dissipation	37	W
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +175	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	85	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	4	$^\circ C/W$

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### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	I <sub>D</sub> = 250mA, V <sub>GS</sub> = 0V	60	-	-	V
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 60V, V <sub>GS</sub> = 0V	-	-	1.0	mA
IGSS	Gate-Body Leakage Current	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250mA	1.2	1.6	2.5	V
RDS(ON)	Static Drain-Source ON-Resistance <sup>(4)</sup>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 10A	-	30	35	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 5A	-	32	45	mΩ
R <sub>g</sub>	Gate Resistance	f = 1MHz	-	1.4	-	Ω
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 30V, f = 1MHz	-	1187	-	pF
C <sub>oss</sub>	Output Capacitance		-	56	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	47	-	pF
Q <sub>g</sub>	Total Gate Charge	V <sub>GS</sub> = 0 to 10V V <sub>DS</sub> = 30V, I <sub>D</sub> = 10A	-	24	-	nC
Q <sub>gs</sub>	Gate Source Charge		-	4.5	-	nC
Q <sub>gd</sub>	Gate Drain("Miller") Charge		-	4.5	-	nC
td(on)	Turn-On DelayTime	V <sub>GS</sub> = 10V, V <sub>DD</sub> = 30V I <sub>D</sub> = 10A, R <sub>GEN</sub> = 3Ω	-	6.7	-	ns
t <sub>r</sub>	Turn-On Rise Time		-	15	-	ns
td(off)	Turn-Off DelayTime		-	24	-	ns
t <sub>f</sub>	Turn-Off Fall Time		-	2.7	-	ns
IS	Maximum Continuous Body Diode Forward Current		-	-	28	A
ISM	Maximum Pulsed Body Diode Forward Current		-	-	79	A
VSD	Body Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = 10A	-		1.2	V
trr	Body Diode Reverse Recovery Time	I <sub>F</sub> = 10A, di/dt = 100A/us	13	19	25	ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge		-	19	-	nC

**Note :**

- 1、 The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3、 The test cond ≅ 300us duty cycle ≅ 2%, duty cycle ition is T<sub>J</sub> =25°C , V<sub>DD</sub> =48V, V<sub>G</sub> =10V, R<sub>G</sub> =25Ω, L=0.1mH, I<sub>AS</sub> =13A
- 4、 The power dissipation is limited by 175°C junction temperature
- 5、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

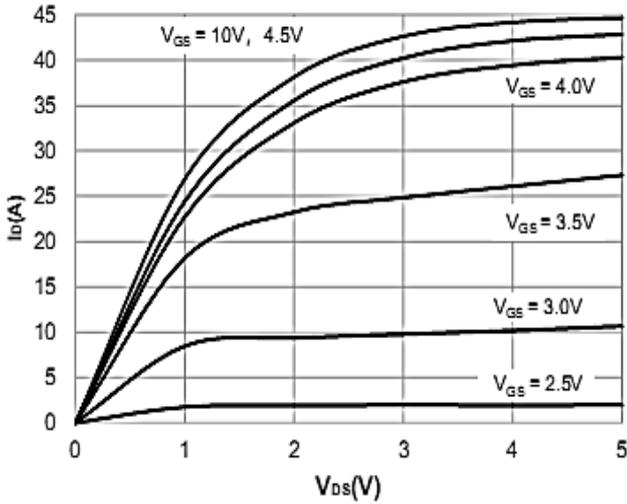


Figure 1: Output Characteristics

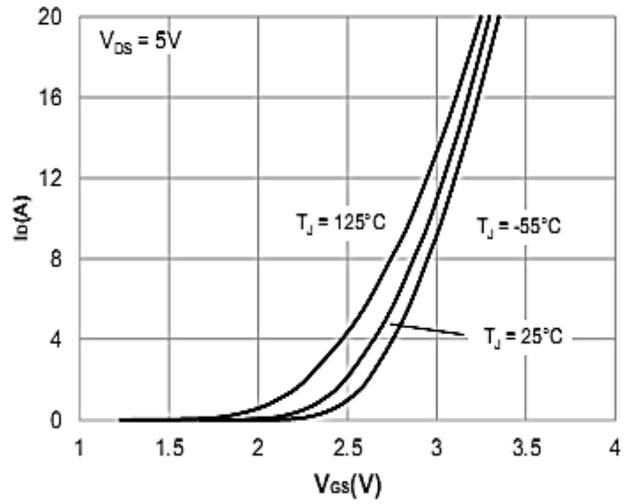


Figure 2: Typical Transfer Characteristics

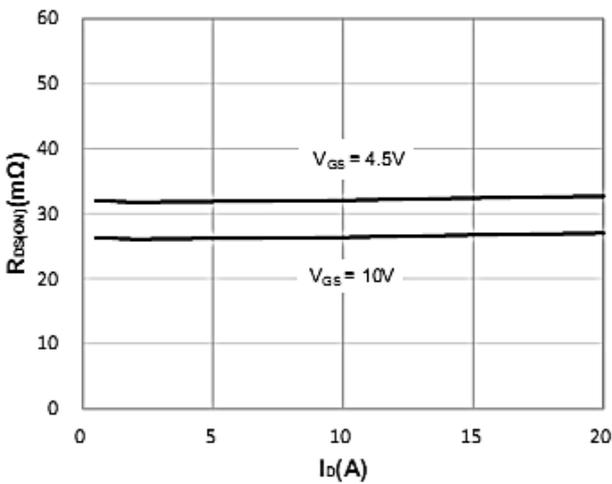


Figure 3: On-resistance vs. Drain Current

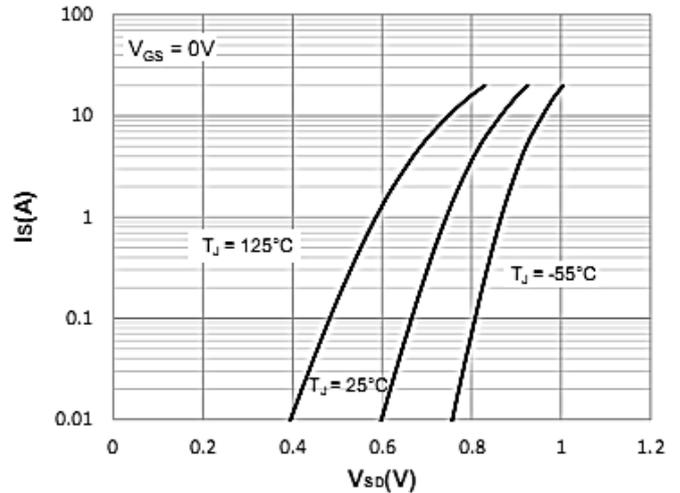


Figure 4: Body Diode Characteristics

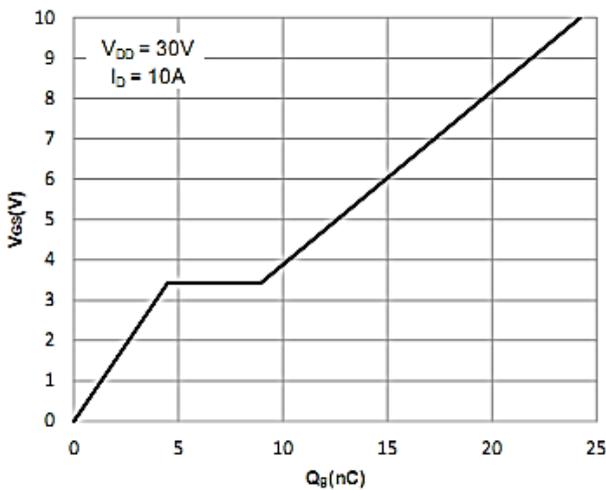


Figure 5: Gate Charge Characteristics

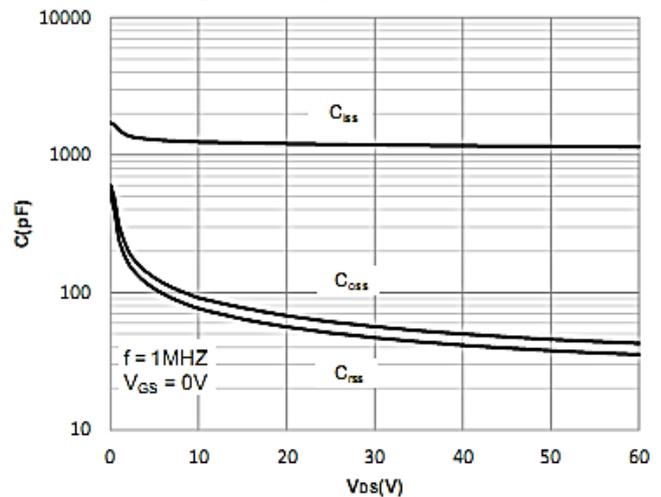
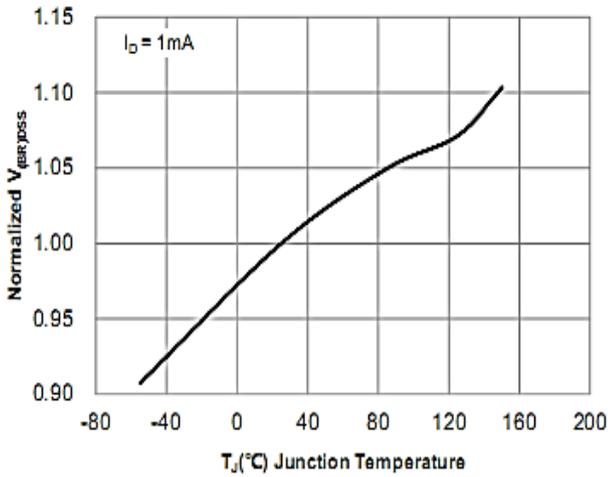


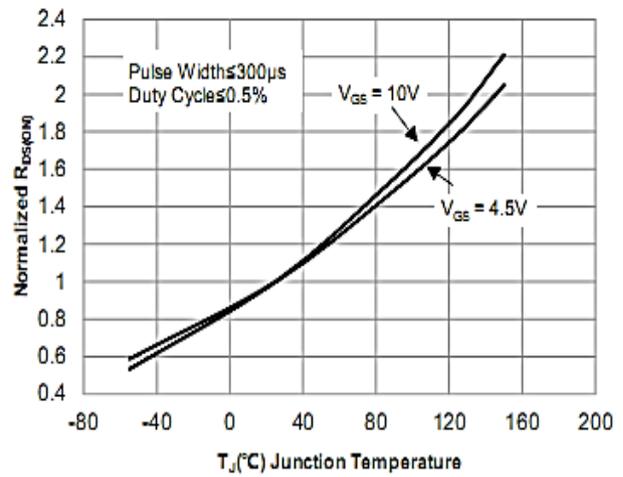
Figure 6: Capacitance Characteristics



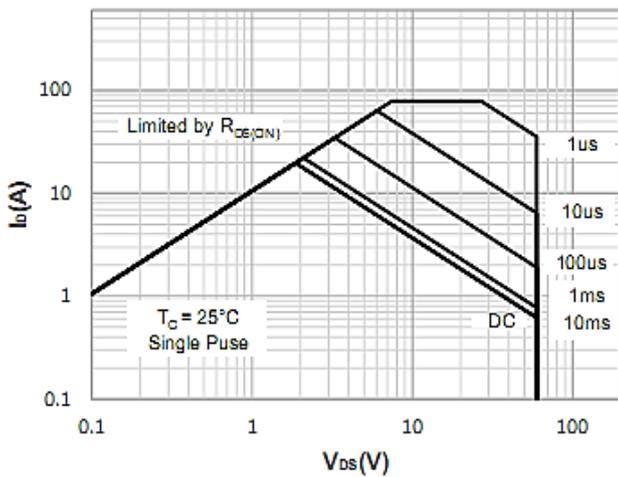
**60V N-Channel Enhancement Mode MOSFET**



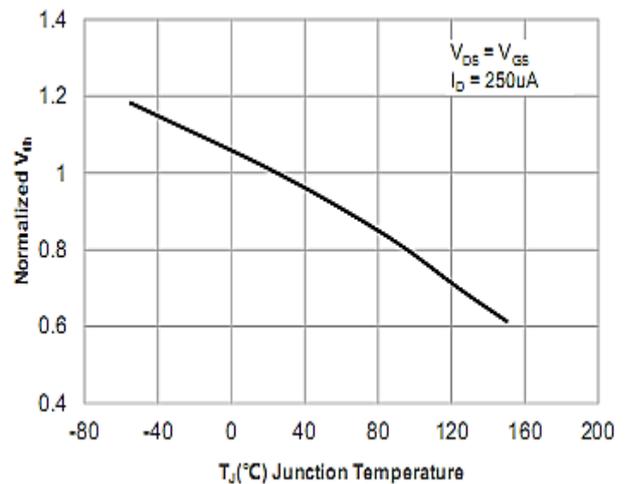
**Figure 7: Normalized Breakdown voltage vs. Junction Temperature**



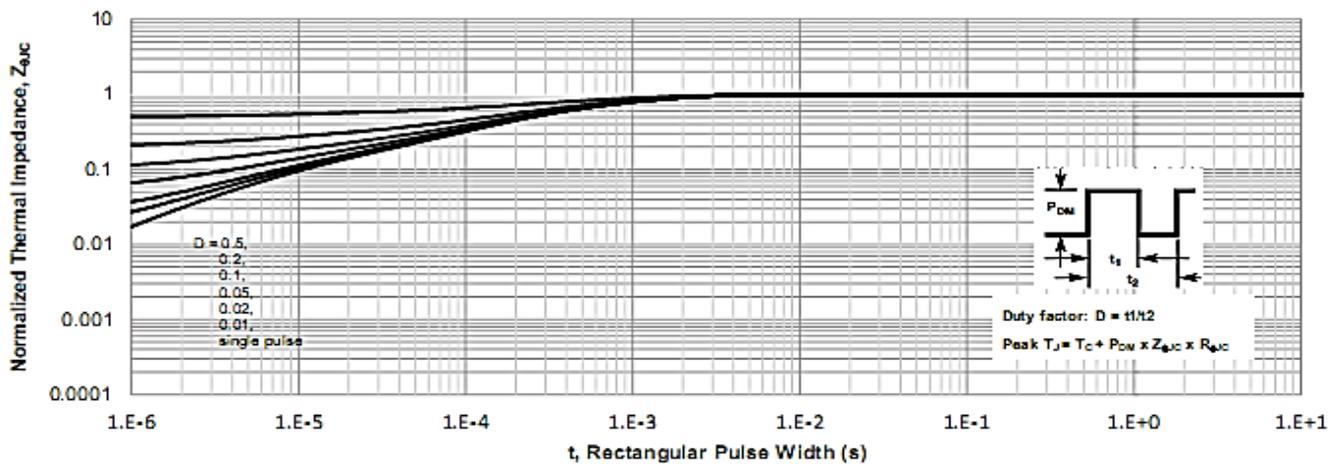
**Figure 8: Normalized on Resistance vs. Junction Temperature**



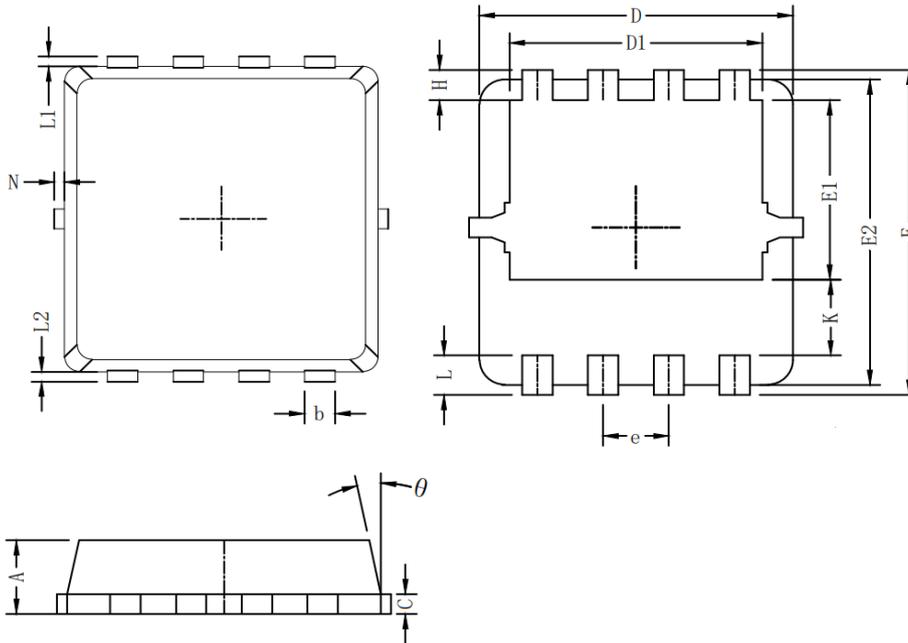
**Figure 9: Maximum Safe Operating Area**



**Figure 10: Normalized Threshold Voltage vs. Junction Temperature**



**Figure 11: Normalized Maximum Transient Thermal Impedance**

**Package Mechanical Data-PDFN3X3-8L**


Symbol	Dim in mm		
	Min	Typ	Max
A	0.6	0.75	0.9
b	0.2	0.3	0.4
C	0.15	0.2	0.25
D	3	3.1	3.2
D1	2.3	2.45	2.6
E	3.15	3.3	3.45
E1	1.43	1.73	1.93
E2	2.9	3.05	3.2
e	0.65BSC		
H	0.2	0.35	0.5
K	0.57	0.77	0.87
L	0.3	0.4	0.5
L1/L2	0.1REF		
θ	8°	10°	13°
N	0		0.15

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Edition	Date	Change
REV1.0	2024/5/23	Initial release

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